Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	٢
10/630,977	LEE ET AL.	
Examiner	Art Unit	
TAN X. DINH	2627	

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOT (INCLUDING SEARCH	ES STRATEGY)
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EAST (see search history printout)	9/14/2006	T.D
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